

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10777470	LEE ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Mui, Christine T	1709

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
204	450	07.11.2007	CTM
366	341	07.11.2007	CTM
422	100, 101	07.11.2007	CTM
435	287.3	07.11.2007	CTM
436	052	07.11.2007	CTM
516	073	07.30.2007	CTM

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
See EAST Search Report	07.10.2007	CTM
See Updated EAST Search Report	07 April 2008	CTM

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>